

Notice of References Cited	Application/Control No. 10/521,703		Applicant(s)/Patent Under Reexamination KUIJPER ET AL.	
	Examiner Henok G. Heyi		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0031954 A1	02-2003	Kakuta et al.	430/270.2
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1143432 A2	10-2001	European Patent	OHNO et al.	G11B 07/24
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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